

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

Applicants:	CHANG et al.	Docket No.:	372465-01401 (341565)
Serial No.:	10/669,496	Group Art Unit:	2825
Filed:	September 23, 2003	Examiner:	Siek, Vuthe
For:	METHOD FOR FASTER TIMING CLOSURE AND BETTER QUALITY OF RESULTS IN IC PHYSICAL DESIGN		

Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

**REQUEST FOR CONTINUED EXAMINATION (RCE)
UNDER 37 CFR § 1.114**

Sir:

A Request for Continued Examination (RCE) of the above-referenced application is hereby submitted.